

- **Four Independent Drivers and Receivers**
- **Driver Slew Rate Controlled by a Single Resistor**
- **Fast Driver Transition Times Down to 1.5 μ s and Receiver Transition Times of 20 ns Typ**
- **Internal Thermal-Overload Protection**
- **RS-423-B Inputs and Outputs Designed to Withstand ± 25 V**
- **ESD Protection Exceeds 2000 V Per MIL-STD-883C Method 3015**
- **LinBICMOS™ Process Technology**

description

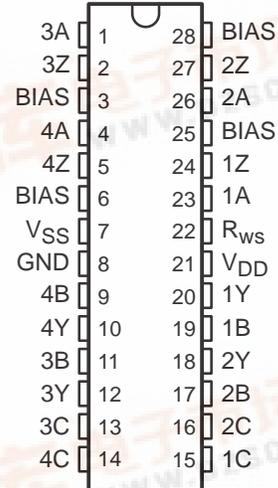
The SN75LBC784 performs as four independent RS-423-B driver/receiver pairs designed to interface data terminal equipment (DTE) with data circuit-terminating equipment (DCE) at rates up to 120 kbps and distances to 1.2 km. The SN75LBC784 provides an upgrade to the RS-232 serial interface and can be backward compatible with existing serial ports while offering the higher performance required by new faster peripherals, such as v.34 (v.fast) modems. The RS-232 standard, and subsequent revisions, only support data rates up to 20 kbps over about 15 meters of cable. For RS-423-B the data rate is increased to 120 kbps and transmission distance to 1.2 km by reducing the maximum output signal swing, increasing the driver output current, and reducing the receiver input voltage thresholds.

The receivers consist of differential comparators with hysteresis and resistive attenuation on the inputs. The resistive attenuation improves the input common mode range and also provides additional protection from ESD and over-voltage stress. The differential and common mode input impedances are sufficiently high to meet RS-423-B. When a differential voltage input of 500 mV is applied across the entire common mode range (see Figure 5), the receiver characteristics and bias voltage allow the receiver to remain in its intended binary state.

The drivers meet all RS-423-B specifications with built-in current limits and thermal-overload protection. Slew-rate controlling circuitry is included in the design, which is adjusted to suit the application by means of an external resistor (R_{WS}). The slew rate controlling circuitry also has a default mode – if the R_{WS} pin is shorted to 5 V externally, the transition time defaults to approximately 1.5 ms. The BIAS input, when shorted to 5 V externally, provides the internal node voltages. The receiver is compatible to RS-232 with the use of external input resistors to meet the RS-232 input resistance specification of 3 k Ω to 7 k Ω .

The SN75LBC784 is characterized for operation over the temperature range of 0°C to 70°C.

DW PACKAGE
(TOP VIEW)



FUNCTION TABLE

INPUTS			OUTPUTS	
A	B	C	Z	Y
L	L	H	H	H
H	L	H	H	L
L	H	L	L	H
H	H	L	L	L
L	L	L	?	H
H	L	L	?	L
L	H	H	?	H
H	H	H	?	L

H = high level, L = low level,
 X = irrelevant, Z = high impedance (off)
 ? = indeterminate



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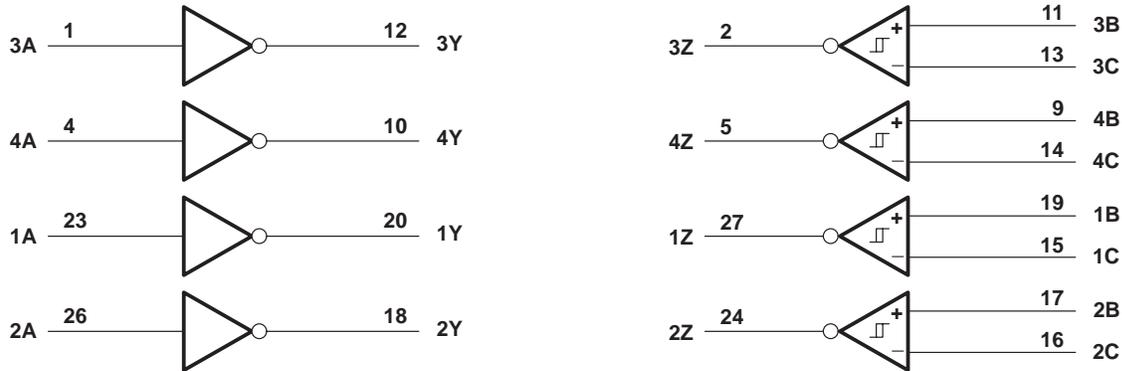
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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Positive supply voltage, V_{DD} (see Note 1)	14 V
Negative supply voltage, V_{SS}	-14 V
Bias voltage, V_{bias}	5.75 V
Receiver input voltage range	-30 V to 30 V
Driver input voltage range	-0.5 V to 5.75 V
Driver output voltage range (supplies at 0 V)	-30 V to 30 V
Driver output voltage range (supplies at ± 12 V)	-25 V to 25 V
Continuous power dissipation	See Dissipation Rating Table
Operating free-air temperature range, T_A	0°C to 70°C
Storage temperature range	-65°C to 150°C
Case temperature for 10 seconds	260°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltages are with respect to network ground terminal.

DISSIPATION RATING TABLE

PACKAGE	$T_A \leq 25^\circ\text{C}$ POWER RATING	DERATING FACTOR† ABOVE $T_A = 25^\circ\text{C}$	$T_A = 70^\circ\text{C}$ POWER RATING
DW	1348 mW	10.8 mW/°C	862 mW

† Derating factors are the inverse of the junction-to-ambient thermal resistance when board-mounted with no air flow.

recommended operating conditions

		MIN	NOM	MAX	UNIT
Supply voltage, V_{DD}		10.8	12	13.2	V
Supply voltage, V_{SS}		-10.8	-12	-13.2	V
Bias voltage, V_{bias}		2	5	5.5	V
High-level input voltage, V_{IH}	Driver	2			V
Low-level input voltage, V_{IL}	Driver			0.8	V
High-level output current, I_{OH}	Receiver			-4	mA
Low-level output current, I_{OL}	Receiver			4	mA
Rws slew rate control resistor		20	82	820	k Ω
Operating free-air temperature, T_A		0		70	°C

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DRIVER SECTION

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature, $V_{DD} = 10.8\text{ V to }13.2\text{ V}$, $V_{SS} = -10.8\text{ V to }-13.2\text{ V}$, $T_A = 0^\circ\text{C to }70^\circ\text{C}$ (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
V_{OH}	High-level output voltage	Open circuit or $R_L = 450\ \Omega$	4	5.5	6	V
V_{OL}	Low-level output voltage	Open circuit or $R_L = 450\ \Omega$	-6	-5.5	-4	V
I_{IH}	High-level input current	$V_I = 2.4\text{ V to }5.5\text{ V}$			100	μA
I_{IL}	Low-level input current	$V_I = 0\text{ V to }0.8\text{ V}$	-100			μA
I_O	Output leakage current	$V_{DD} = V_{SS} = 0$, $V_O = \pm 6\text{ V}$	-100		100	μA
$I_{OS(H)}$	High-level short circuit output current	$V_I = 5\text{ V}$, $V_O = 0$	15		45	mA
$I_{OS(L)}$	Low-level short circuit output current	$V_I = 0$, $V_O = 0$	-45		-15	mA
I_{DD}	Supply current	No load		10	12	mA
		$R_L = 450\ \Omega$		60	70	
I_{SS}	Supply current	No load		-10	-12	mA
		$R_L = 450\ \Omega$		-60	-70	
I_{bias}	Bias current				400	μA

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $V_{DD} = 10.8\text{ V to }13.2\text{ V}$, $V_{SS} = -10.8\text{ V to }-13.2\text{ V}$, $T_A = 0^\circ\text{C to }70^\circ\text{C}$ (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT	
t_{TLH}	Transition time, low-to-high level (see Figure 1)	$R_L = 450\ \Omega$, $V_{WS} = 5\text{ V}$	$C_L = 50\text{ pF}$,	$R_{WS} = 0\text{ k}\Omega$		1.5	μs	
				$R_{WS} = 20\text{ k}\Omega$	1.5	2.1		2.7
				$R_{WS} = 82\text{ k}\Omega$	5	8		11
				$R_{WS} = 820\text{ k}\Omega$		80		
t_{THL}	Transition time, high-to-low level (see Figure 1)			$R_{WS} = 0\text{ k}\Omega$		1.5		μs
				$R_{WS} = 20\text{ k}\Omega$	1.5	2.1	2.7	
				$R_{WS} = 82\text{ k}\Omega$	5	8	11	
				$R_{WS} = 820\text{ k}\Omega$		80		
SR	Output slew rate					15	V/ μs	
t_{sk}	Output skew (see Figure 4) $ t_{PHL} - t_{PLH} $					1	μs	

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RECEIVER SECTION

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature, $V_{DD} = 10.8\text{ V to }13.2\text{ V}$, $V_{SS} = -10.8\text{ V to }-13.2\text{ V}$, $T_A = 0^\circ\text{C to }70^\circ\text{C}$ (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT	
V_{IT+}	Positive input threshold voltage				200	mV	
		With 500 Ω series resistor			400		
V_{IT-}	Negative input threshold voltage				-200	mV	
		With 500 Ω series resistor			-400		
I_I	Input current	$V_I = 10\text{ V}$	Other input to GND		1.3	3.25	mA
		$V_I = -10\text{ V}$			-3.25	-1.3	
V_{hys}	Hysteresis ($V_{IT+} - V_{IT-}$)		20	40	150	mV	
V_{OH}	High-level output voltage (see Note 2)	$I_O = -20\ \mu\text{A}$			3.5	5	V
		$I_O = -4\text{ mA}$			2.4	5	
V_{OL}	Low-level output voltage	$I_O = 20\ \mu\text{A to }4\text{ mA}$				0.4	V
I_{RX}	RX short circuit current					50	mA
V_{ID}	Differential input voltage	Receiver inputs open circuit	1.6	2.1	2.6	V	
V_{ofs}	Fail safe output voltage	See Note 3	3.5			V	

- NOTES: 2. Device has an internal RX supply regulator. Maximum RX logic output voltage under no load is thus defined by an internal voltage value. This is nominally set to 4.5 V with a tolerance of $\pm 5\%$.
3. One input at ground, other input open circuit, $I_O = -20\ \mu\text{A}$, or both open circuit.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

test conditions: $V_{DD} = 10.8\text{ V to }13.2\text{ V}$, $V_{SS} = -10.8\text{ V to }-13.2\text{ V}$, $T_A = 0^\circ\text{C to }70^\circ\text{C}$ (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	NOM	MAX	UNIT
t_{PLH}	Propagation Delay time low-to-high (see Figure 2)	$C_L = 50\text{ pF}$		0.15	1	μs
t_{PHL}	Propagation delay time high-to-low (see Figure 2)					
t_{THL}	Transition time high-to-low (see Figure 3)			20	200	ns
t_{TLH}	Transition time low-to-high (see Figure 3)					

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PARAMETER MEASUREMENT INFORMATION

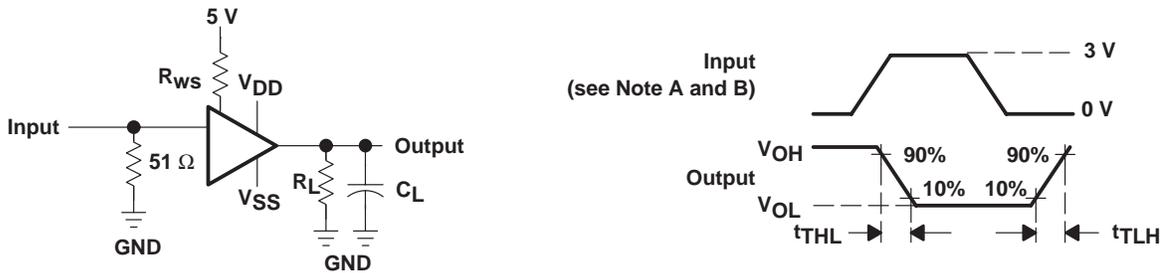


Figure 1. Driver Transition Times

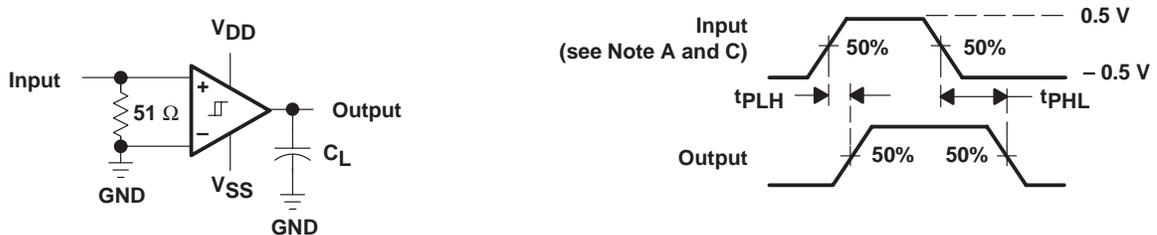


Figure 2. Receiver Propagation Delay Times

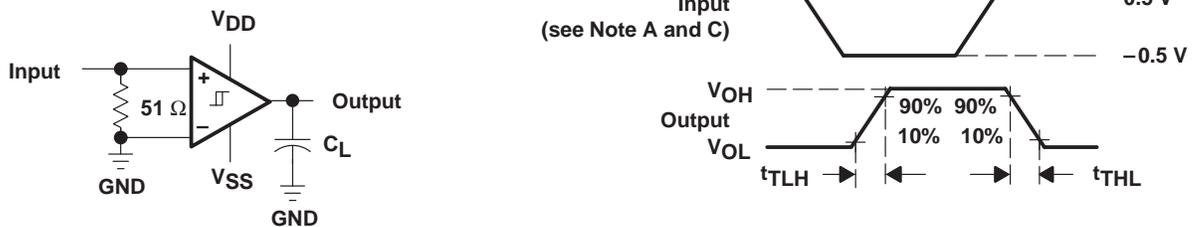


Figure 3. Receiver Transition Times

- NOTES: A. C_L includes probe and jig capacitance.
 B. The input pulse is supplied by a generator having the following characteristics: $t_r \leq 10$ nS, $t_f < 10$ nS, $Z_0 = 50 \Omega$, $PRR \geq 5$ kHz, duty cycle 50%, $V_{max} = 3$ V, $V_{min} = 0$ V.
 C. The input pulse is supplied by a generator having the following characteristics: $t_r \leq 10$ nS, $t_f < 10$ nS, $Z_0 = 50 \Omega$, $PRR \geq 5$ kHz, duty cycle 50%, $V_{max} = 0.5$ V, $V_{min} = -0.5$ V.

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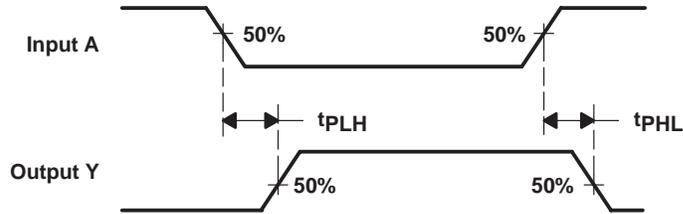


Figure 4. Skew Definition Times

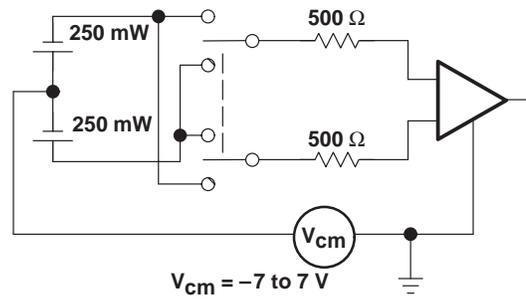


Figure 5. Receiver Input Balance Test

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